IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Narain et al.	
Application No.: Not yet known	**Examiner:** Not yet known
Filed: Herewith	**Art Unit:** Not yet known
For: Intent-Driven Functional Verification of Digital Designs	**Confirmation No.:** Not yet known

Express

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INFORMATION DISCLOSURE STATEMENT
Under 37 C.F.R. 1.97(b)(3) and 1.98

Sir:

The Examiner is requested to consider the references noted on the enclosed From PTO-1449 during examination of the above-identified patent application. These references are submitted for the Examiner's consideration and are submitted pursuant to the duty of disclosure under 37 C.F.R. § 1.56. In submitting these references, no representation is made or implied that the references are or are not material to the examination of the application. The Examiner is encouraged to make his or her own determination of materiality.
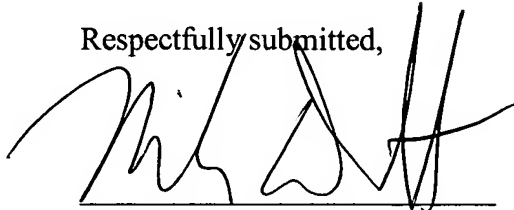
Copies of the cited documents have been previously furnished to or cited by the Office in prior Application No. 09/566,684, filed May 8, 2000. Therefore, copies of the cited documents are not included herewith.

Pursuant to 37 C.F.R. § 1.97(b)(3), no fees are due with respect to this filing. However, should any fees be deemed necessary, such fees may be charged to Deposit Account No. 06-0029.

If the Examiner has any questions concerning the relevance of any reference cited in this disclosure, please contact the undersigned attorney.

Dated: 11/18/03

Respectfully submitted,

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 59165-298553	APPLN. NO. Not yet known
INFORMATION DISCLOSURE STATEMENT BY APPLICANT	APPLICANT: NARAIN et al.	
(Use several sheets if necessary)	FILING DATE Herewith	GROUP Not yet known

U.S. PATENT DOCUMENTS

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FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NUMBER	PUBLISHED DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
		PCT/US01/14973	03-11-02	Europe				

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